## Application/Control No. | Applicant(s)/Patent Under Reexamination | WU ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	. Name	Classification
	Α	US-5,843,569	12-1998	Kaitsu et al.	428/323
	В	US-2003/0157370	08-2003	Nakamura et al.	428/694.0BA
	С	US-2003/0219630	11-2003	Moriwaki et al.	428/694.00R
	D	US-2002/0136929	09-2002	Oikawa et al.	428/694.0TM
	Е	US-6,177,208	01-2001	Yamamoto et al.	428/692
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	м	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Ø					
	R					
	s					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	v	·
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.